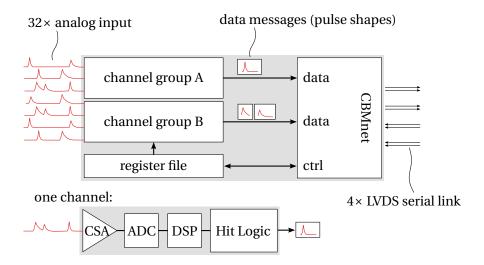
Status of SPADIC 1.0 FEE

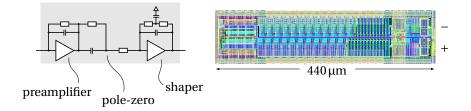
Michael Krieger

23rd CBM Collaboration Meeting 07.04.2014, GSI

Reminder: SPADIC 1.0 architecture



Charge sensitive amplifier



- input range: 75 fC
- $h(t) \propto t \cdot e^{-t/\tau}$ (in: current, out: voltage)
- shaping time: $\tau = 80 \text{ ns}$

two amplifiers per channel selectable:

- positive polarity (4–5 mW)
- negative polarity (10 mW, not optimized)

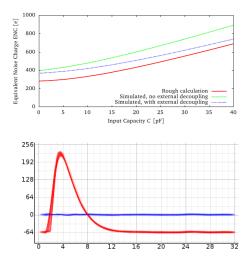
layout & schematics: modular, scalable

CSA characterization

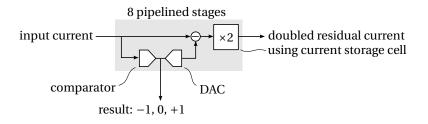
- simulation + previous testchips: ENC = 800 e⁻ @ 30 pF (300 e⁻ @ 0 pF)
- tuning of bias settings → local noise minimum

• ENC =
$$\frac{q}{S/N(q)} = q \cdot \frac{\sigma}{h(q)}$$

- $q \stackrel{?}{=} 1.8 \text{V} \cdot 15(?) \text{ fF}$
- $S/N \le 180$ (CSA + ADC)



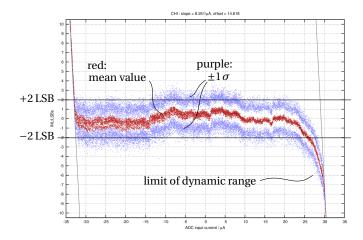
ADC



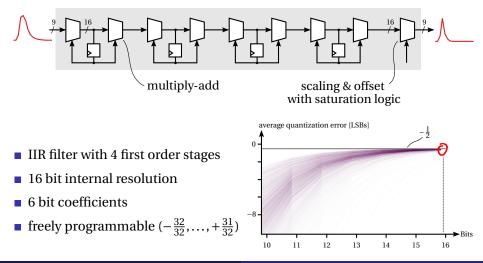
- current mode pipelined design
- 25 MHz sample rate, continuously running
- 9 bit nominal output (2's complement)
- resolution ≈ 8 bits
- 4.8 mW, rad-hard layout, $400 \times 300 \,\mu\text{m}^2$

ADC measurements

INL + noise: taken at 20 MHz sample rate, preliminary bias settings



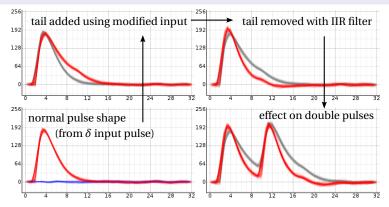
Digital signal processing



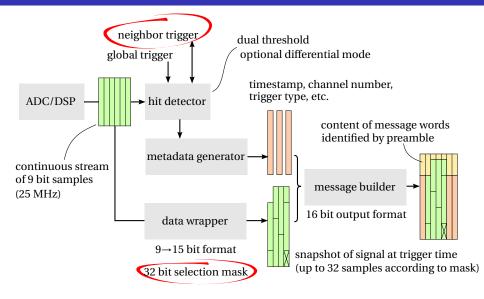
Digital signal processing

purpose: "ion tail" cancellation

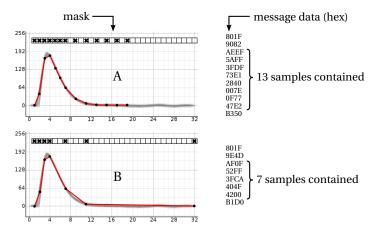
shorten pulses \rightarrow reduce pileup/help hit logic



Hit logic



Selection mask examples

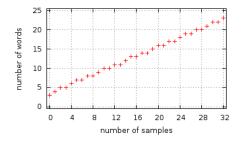


→ allows tradeoff between quality of signal reconstruction and data volume

Message size (selection mask)

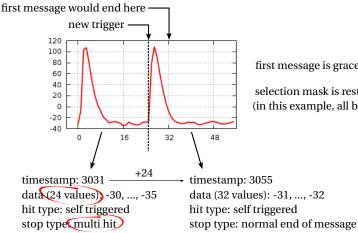
$$n_{\text{words}} = 3 + \left[\frac{9 \times n_{\text{samples}} + 3}{15}\right] \quad \text{for} \quad 1 \le n_{\text{samples}} \le 32$$
$$n_{\text{words}} = 3 \quad \text{for} \quad n_{\text{samples}} = 0$$

minimal message: 3 words (no samples, only metadata)



Multi hits

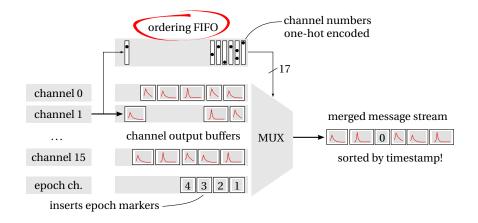
What happens when a channel is triggered again, before the current message is completed?



first message is gracefully aborted

selection mask is restarted (in this example, all bits are selected...) SPADIC feature overview

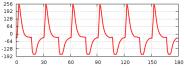
Message output multiplexing



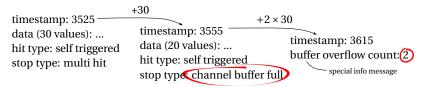
Error handling

What happens when a channel output buffer is full? Test case:

input signal: square wave, period = 30 time bins (>600 kHz hit rate) reconstructed output signal: no problem with only one channel active



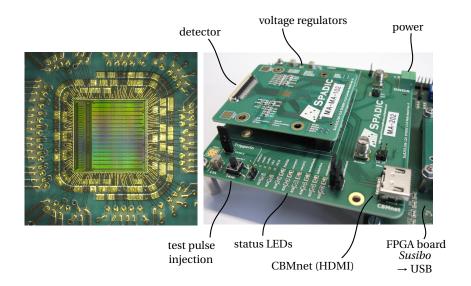
force buffer overflow with neighbor trigger \rightarrow MUX can't read fast enough



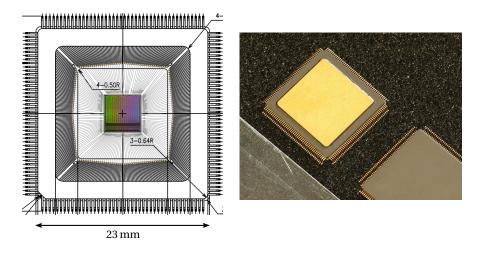
 \rightarrow Similarly for ordering FIFO, incl. handling of flipped bits (SEU).

Test setups

Current test setup: FEB rev. A + Susibo



Packaging: QFP176



Test setups

New FEB rev. B (using QFP176, 1x and 3x versions)



- finish assembly of first rev.B1x FEB
- test it using Susibo readout
- port Susibo firmware → Syscore3
- verify SPADIC/Syscore3 connection (using USB)
- merge into "official" Syscore3 firmware (using optical FLIB readout)
- produce rev.B3x FEBs once 1x is tested

The End.